Substitute for form 1449A/PTO 8 1449B/PTO Complete if Known **Application Number** 10/743,815 **FIRST INFORMATION DISCLOSURE** Filing Date December 24, 2003 STATEMENT BY APPLICANT **First Named Inventor** Daniel Krähmer, et al. **Examiner Name** Unassigned (use as many sheets as necessary) Sheet of 1 **Attorney Docket Number** 007413-071 1

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conformance and not considered. Include copy of this form with next communication to Applicant.